## General Description

The SLG59H1009V is a high-performance, self-powered $13.1 \mathrm{~m} \Omega$ NMOS power switch designed for all 4.5 V to 22 V power rails up to 4 A . Using a proprietary MOSFET design, the SLG59H1009V achieves a stable $13.1 \mathrm{~m} \Omega$ RDS $_{\text {ON }}$ across a wide input voltage range. In combining novel FET design and copper pillar interconnects, the SLG59H1009V package also exhibits a low thermal resistance for high-current operation.
Designed to operate over a $-40{ }^{\circ} \mathrm{C}$ to $85{ }^{\circ} \mathrm{C}$ range, the SLG59H1009V is available in a low thermal resistance, RoHS-compliant, $1.6 \times 3.0 \mathrm{~mm}$ STQFN package.

## Features

- UL2367 Certified - File Number E468659
- Maximum Continuous Current: 4 A
- Automatic nFET SOA Protection
- High-performance MOSFET Switch Low RDS $_{\mathrm{ON}}: 13.1 \mathrm{~m} \Omega$ at $\mathrm{V}_{\mathrm{IN}}=22 \mathrm{~V}$
Low $\Delta$ RDS $_{\mathrm{ON}} / \Delta \mathrm{V}_{\mathrm{IN}}:<0.05 \mathrm{~m} \Omega / \mathrm{V}$
Low $\Delta \mathrm{RDS}_{\mathrm{ON}} / \Delta \mathrm{T}:<0.06 \mathrm{~m} \Omega /{ }^{\circ} \mathrm{C}$
- Capacitor-adjustable Inrush Current Control
- Two stage Current Limit Protection:

Resistor-adjustable Active Current Limit Internal Short-circuit Current limit

- Open Drain FAULT Signaling
- MOSFET Current Analog Output Monitor: $10 \mu \mathrm{~A} / \mathrm{A}$
- Fast $4 \mathrm{k} \Omega$ Output Discharge
- Pb-Free / Halogen-Free / RoHS Compliant Packaging

Pin Configuration

$1.6 \times 3.0 \mathrm{~mm}, 0.40 \mathrm{~mm}$ pitch
(Top View)

## Applications

- Power-Rail Switching
- Multifunction Printers
- Large-format Copiers
- Telecommunications Equipment
- High-performance Computing
$5 \mathrm{~V}, 9 \mathrm{~V}, 12 \mathrm{~V}$, and 20 V Point-of-Load Power Distribution
- Motor Drives

Block Diagram and a 20 V / 3 A Typical Application Circuit


## Pin Description

| Pin \# | Pin Name | Type | Pin Description |
| :---: | :---: | :---: | :---: |
| 1 | ON | Input | A low-to-high transition on this pin initiates the operation of the SLG59H1009V's state machine. ON is an asserted HIGH, level-sensitive CMOS input with $\mathrm{ON}_{\mathrm{I}} \mathrm{V}_{\mathrm{IL}}<0.3 \mathrm{~V}$ and $\mathrm{ON}_{\mathrm{N}} \mathrm{V}_{\mathrm{IH}}>0.9 \mathrm{~V}$. As the ON pin input circuit does not have an internal pull-down resistor, connect this pin to a general-purpose output (GPO) of a microcontroller, an application processor, or a system controller - do not allow this pin to be open-circuited. |
| 2 | SELO | Input | As level-sensitive, CMOS inputs with $\mathrm{V}_{\mathrm{IH}}>1.65 \mathrm{~V}$, the SEL0 (LSB) and the SEL1 (MSB) pins set the $\mathrm{V}_{\text {IN }}$ overvoltage lockout threshold. A logic HIGH on either pin is achieved by connecting a $10 \mathrm{k} \Omega$ external resistor from the pin in question to the system's local logic supply. |
| 3 | GND | GND | Pin 3 is the main ground connection for the SLG59H1009V's internal charge pump, its gate driver and current-limit circuits as well as its internal state machine. Therefore, use a short, stout connection from Pin 3 to the system's analog or power plane. |
| 4-8 | VIN | MOSFET | VIN supplies the power for the operation of the SLG59H1009V, its internal control circuitry, and the drain terminal of the nFET power switch. With 5 pins fused together at VIN, connect a $47 \mu \mathrm{~F}$ (or larger) low-ESR capacitor from this pin to ground. Capacitors used at VIN should be rated at 50 V or higher. |
| 9-13 | VOUT | MOSFET | Source terminal of n-channel MOSFET ( 5 pins fused for VOUT). Connect a $47 \mu \mathrm{~F}$ (or larger) low-ESR capacitor from this pin to ground. Capacitors used at VOUT should be rated at 50 V or higher. |
| 14 | SEL1 | Input | Please see SELO Pin Description above |
| 15 | $\overline{\text { FAULT }}$ | Output | An open drain output, $\overline{\text { FAULT }}$ is asserted within $\overline{F A U L T}_{\text {Low }}$ when a $\mathrm{V}_{\text {IN }}$ overvoltage, a current-limit, or an over-temperature condition is detected. FAULT is deasserted within $\overline{\mathrm{TFAULT}}_{\text {HIGH }}$ when the fault condition is removed. Connect an $100 \mathrm{k} \Omega$ external resistor from the $\overline{\text { FAULT }}$ pin to local system logic supply. |
| 16 | CAP | Output | A low-ESR, stable dielectric, ceramic surface-mount capacitor connected from CAP pin to GND sets the $\mathrm{V}_{\text {OUT }}$ slew rate and overall turn-on time of the SLG59H1009V. For best performance, the range for $\mathrm{C}_{\text {SLEW }}$ values are $10 \mathrm{nF} \leq \mathrm{C}_{\text {SLEW }} \leq 20 \mathrm{nF}$ - please see typical characteristics for additional information. Capacitors used at the CAP pin should be rated at 10 V or higher. Please consult Applications Section on how to select $\mathrm{C}_{\text {SLEW }}$ based on $\mathrm{V}_{\text {OUT }}$ slew rate and loading conditions. |
| 17 | IOUT | Output | IOUT is the SLG59H1009V's power MOSFET load current monitor output. As an analog current output, this signal when applied to a ground-reference resistor generates a voltage proportional to the current through the n-channel MOSFET. The I IUTT transfer characteristic is typically $10 \mu \mathrm{~A} / \mathrm{A}$ with a voltage compliance range of $0.5 \mathrm{~V} \leq \mathrm{V}_{\text {IOUT }} \leq 4 \mathrm{~V}$. Optimal I I exhibited for $0.5 \mathrm{~A} \leq \mathrm{I}_{\mathrm{DS}} \leq 4 \mathrm{~A}$. In addition, it is recommended to bypass the IOUT pin to GND with a 0.18 nF capacitor. |
| 18 | RSET | Input | A $1 \%$-tolerance, metal-film $21 \mathrm{k} \Omega$ resistor sets the active current limit of the SLG59H1009V to 4.5 A. |

## Ordering Information

| Part Number | Type | Production Flow |
| :---: | :---: | :---: |
| SLG59H1009V | STQFN 18L FC | Industrial, $-40^{\circ} \mathrm{C}$ to $85^{\circ} \mathrm{C}$ |
| SLG59H1009VTR | STQFN 18L FC (Tape and Reel) | Industrial, $-40^{\circ} \mathrm{C}$ to $85^{\circ} \mathrm{C}$ |

with $\mathrm{V}_{\text {IN }}$ Lockout Select and MOSFET Current Monitor Output

## Absolute Maximum Ratings

| Parameter | Description | Conditions | Min. | Typ. | Max. | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| $\mathrm{V}_{\text {IN }}$ to GND | Power Switch Input Voltage to GND | Continuous | -0.3 | -- | 30 | V |
|  |  | Maximum pulsed $\mathrm{V}_{\text {IN }}$, pulse width < 0.1 s | -- | -- | 32 | V |
| $V_{\text {OUt }}$ to GND | Power Switch Output Voltage to GND |  | -0.3 | -- | VIN | V |
| ON, SEL[1,0], CAP, RSET, IOUT, and FAULT to GND | ON, SEL[1,0], CAP, RSET, IOUT, and FAULT Pin Voltages to GND |  | -0.3 | -- | 7 | V |
| $\mathrm{T}_{\mathrm{S}}$ | Storage Temperature |  | -65 | -- | 150 | ${ }^{\circ} \mathrm{C}$ |
| ESD ${ }_{\text {HBM }}$ | ESD Protection | Human Body Model | 2000 | -- | -- | V |
| ESD ${ }_{\text {CDM }}$ | ESD Protection | Charged Device Model | 500 | -- | -- | V |
| MSL | Moisture Sensitivity Level |  |  | 1 |  |  |
| $\theta_{\text {JA }}$ | Thermal Resistance | $1.6 \times 3.0 \mathrm{~mm}$ 18L STQFN; Determined with the device mounted onto a $1 \mathrm{in}^{2}$, 1 oz . copper pad of FR-4 material | -- | 40 | -- | ${ }^{\circ} \mathrm{C} / \mathrm{W}$ |
| MOSFET IDS ${ }_{\text {CONT }}$ | Continuous Current from VIN to VOUT | $\mathrm{T}_{\mathrm{J}}<150^{\circ} \mathrm{C}$ | -- | -- | 4 | A |
| MOSFET IDS ${ }_{\text {PEAK }}$ | Peak Current from VIN to VOUT | Maximum pulsed switch current, pulse width < 1 ms | -- | -- | 5 | A |

Note: Stresses greater than those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability.

## Electrical Characteristics

$\mathrm{V}_{\text {IN }}=22 \mathrm{~V} ; \mathrm{C}_{\text {IN }}=47 \mu \mathrm{~F}, \mathrm{~T}_{\mathrm{A}}=-40^{\circ} \mathrm{C}$ to $85^{\circ} \mathrm{C}$, unless otherwise noted. Typical values are at $\mathrm{T}_{\mathrm{A}}=25^{\circ} \mathrm{C}$

| Parameter | Description | Conditions | Min. | Typ. | Max. | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| $\mathrm{V}_{\text {IN }}$ | Operating Input Voltage |  | -- | 20 | 22 | V |
| $\mathrm{V}_{\text {IN(OVLO }}$ | $\mathrm{V}_{\text {IN }}$ Overvoltage Lockout Threshold | $\mathrm{V}_{\text {IN }} \uparrow$; SEL[1,0] = [1,1] | 22.7 | 24 | 25.2 | V |
| $\mathrm{V}_{\text {IN(UVLO) }}$ | $\mathrm{V}_{\text {IN }}$ Undervoltage Lockout Threshold | $\vee_{\text {IN }} \downarrow$ | 2.4 | -- | 3.8 | V |
| $\mathrm{I}_{\mathrm{Q}}$ | Quiescent Supply Current | $\mathrm{ON}=\mathrm{HIGH} ; \mathrm{I}_{\text {DS }}=0 \mathrm{~A}$ | -- | 0.5 | 0.6 | mA |
| $\mathrm{I}_{\text {SHDN }}$ | OFF Mode Supply Current | ON = LOW; $\mathrm{I}_{\text {S }}=0 \mathrm{~A}$ | -- | 1 | 3 | $\mu \mathrm{A}$ |
| $\mathrm{RDS}_{\text {ON }}$ | ON Resistance | $\mathrm{T}_{\mathrm{A}}=25^{\circ} \mathrm{C} ; \mathrm{l}_{\mathrm{DS}}=0.1 \mathrm{~A}$ | -- | 13.1 | 14 | $\mathrm{m} \Omega$ |
|  |  | $\mathrm{T}_{\mathrm{A}}=85^{\circ} \mathrm{C} ; \mathrm{I}_{\mathrm{DS}}=0.1 \mathrm{~A}$ | -- | 16 | 16.5 | $\mathrm{m} \Omega$ |
| MOSFET IDS | Current from VIN to VOUT | Continuous | -- | -- | 4 | A |
| $\mathrm{I}_{\text {LIMIT }}$ | Active Current Limit, $\mathrm{I}_{\text {ACL }}$ | $\mathrm{V}_{\text {OUT }}>0.5 \mathrm{~V} ; \mathrm{R}_{\text {SET }}=21 \mathrm{k} \Omega$ | 4.2 | 4.5 | 4.9 | A |
|  | Short-circuit Current Limit, $\mathrm{I}_{\text {SCL }}$ | $\mathrm{V}_{\text {OUT }}<0.5 \mathrm{~V}$ | -- | 0.5 | -- | A |
| $\mathrm{T}_{\text {ACL }}$ | Active Current Limit Response Time |  | -- | 120 | -- | $\mu \mathrm{s}$ |
| $\mathrm{R}_{\text {DISCHRG }}$ | Output Discharge Resistance |  | 3.5 | 4.4 | 5.3 | k $\Omega$ |
| Iout | MOSFET Current Analog Monitor Output | $\mathrm{I}_{\mathrm{DS}}=1 \mathrm{~A}$ | 9.3 | 10 | 10.7 | $\mu \mathrm{A}$ |
|  |  | $\mathrm{I}_{\mathrm{DS}}=3 \mathrm{~A}$ | 28.5 | 30 | 31.5 | $\mu \mathrm{A}$ |
| TIOUT | Iout Response Time to Change in Main MOSFET Current | $\mathrm{C}_{\text {IOUT }}=180 \mathrm{pF}$; <br> Step load 0 to $2.4 \mathrm{~A} ; 0 \%$ to $90 \% \mathrm{I}_{\text {OUT }}$ | -- | 45 | -- | $\mu \mathrm{s}$ |

A $22 \mathrm{~V}, 13.1 \mathrm{~m} \Omega$, 4 A Integrated Power Switch
with $\mathrm{V}_{\text {IN }}$ Lockout Select and MOSFET Current Monitor Output

## Electrical Characteristics (continued)

$\mathrm{V}_{\text {IN }}=22 \mathrm{~V} ; \mathrm{C}_{\text {IN }}=47 \mu \mathrm{~F}, \mathrm{~T}_{\mathrm{A}}=-40^{\circ} \mathrm{C}$ to $85^{\circ} \mathrm{C}$, unless otherwise noted. Typical values are at $\mathrm{T}_{\mathrm{A}}=25^{\circ} \mathrm{C}$

| Parameter | Description | Conditions | Min. | Typ. | Max. | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| $\mathrm{C}_{\text {LOAD }}$ | Output Load Capacitance | $\mathrm{C}_{\text {LOAD }}$ connected from VOUT to GND | -- | 47 | -- | $\mu \mathrm{F}$ |
| TON_Delay | ON Delay Time | $50 \%$ ON to $10 \% V_{\text {OUT }} \uparrow$; <br> $\mathrm{V}_{\text {IN }}=22 \mathrm{~V} ; \mathrm{C}_{\text {SLEW }}=10 \mathrm{nF}$; <br> $R_{\text {LOAD }}=100 \Omega, C_{\text {LOAD }}=10 \mu \mathrm{~F}$ | -- | 0.7 | 1.2 | ms |
| $\mathrm{T}_{\text {Total_ON }}$ | Total Turn On Time | $50 \%$ ON to $90 \% \mathrm{~V}_{\text {OUT }} \uparrow$ | Set by External $\mathrm{C}_{\text {SLEW }}{ }^{1}$ |  |  | ms |
|  |  | $50 \%$ ON to $90 \% V_{\text {OUT }} \uparrow$; <br> $\mathrm{V}_{\text {IN }}=22 \mathrm{~V}$; $\mathrm{C}_{\text {SLEW }}=10 \mathrm{nF}$; <br> $R_{\text {LOAD }}=100 \Omega, C_{\text {LOAD }}=10 \mu \mathrm{~F}$ | -- | 5 | 8 | ms |
| $\mathrm{V}_{\text {OUT(SR) }}$ | $V_{\text {Out }}$ Slew rate | $10 \% \mathrm{~V}_{\text {OUT }}$ to $90 \% \mathrm{~V}_{\text {OUT }} \uparrow$ | Set by External $\mathrm{C}_{\text {SLEW }}{ }^{1}$ |  |  | V/ms |
|  |  | $10 \% \mathrm{~V}_{\text {OUT }}$ to $90 \% \mathrm{~V}_{\text {OUT }} \uparrow$; <br> $\mathrm{V}_{\mathrm{IN}}=22 \mathrm{~V} ; \mathrm{C}_{\text {SLEW }}=10 \mathrm{nF}$; <br> $R_{\text {LOAD }}=100 \Omega, C_{\text {LOAD }}=10 \mu \mathrm{~F}$ | 2.7 | 3.2 | 3.9 | V/ms |
| Toff_Delay | OFF Delay Time | $\begin{aligned} & 50 \% \text { ON to } \mathrm{V}_{\text {OUT }} \text { Fall Start } \downarrow ; \\ & \mathrm{V}_{\text {IN }}=22 \mathrm{~V} ; \\ & \mathrm{R}_{\text {LOAD }}=100 \Omega \text {, No } C_{\text {LOAD }} \\ & \hline \end{aligned}$ | -- | 15 | -- | $\mu \mathrm{s}$ |
| $\mathrm{T}_{\text {FALL }}$ | $V_{\text {Out }}$ Fall Time | $\begin{aligned} & 90 \% \mathrm{~V}_{\text {OUT }} \text { to } 10 \% \mathrm{~V}_{\text {OUT }} ; \\ & \text { ON = HIGH-to-LOW; } \mathrm{V}_{\text {IN }}=22 \mathrm{~V} ; \\ & \mathrm{R}_{\text {LOAD }}=100 \Omega, \text { No } \mathrm{C}_{\text {LOAD }} \end{aligned}$ | 10.4 | 12.7 | 14.3 | $\mu \mathrm{s}$ |
| T $\overline{\text { FAULT }}_{\text {Low }}$ | FAULT Assertion Time | Abnormal Step Load Current event to FAULT $\downarrow$; $\mathrm{I}_{\mathrm{ACL}}=4.5 \mathrm{~A} ; \mathrm{V}_{\mathrm{IN}}=22 \mathrm{~V}$; $\mathrm{R}_{\mathrm{SET}}=21 \mathrm{k} \Omega$; switch in $5 \Omega$ load | -- | 80 | -- | $\mu \mathrm{s}$ |
| $\mathrm{T}_{\mathbf{F A U L T}}^{\text {HIGH }}$ | $\overline{\text { FAULT }}$ De-assertion Time | Delay to $\overline{\mathrm{FAULT}} \uparrow$ after fault condition is removed; $\mathrm{I}_{\mathrm{ACL}}=4.5 \mathrm{~A} ; \mathrm{V}_{\mathrm{IN}}=22 \mathrm{~V}$; $R_{\text {SET }}=21 \mathrm{k} \Omega$; switch out $5 \Omega$ load | -- | 180 | -- | $\mu \mathrm{s}$ |
| $\overline{\text { FAULT }}_{\text {Vol }}$ | $\overline{\text { FAULT }}$ Output Low Voltage | $\mathrm{I}_{\overline{\text { FAULT }}}=1 \mathrm{~mA}$ | -- | 0.2 | -- | V |
| $\mathrm{ON} \mathrm{V}_{\mathrm{IH}}$ | ON Pin Input High Voltage |  | 0.9 | -- | 5 | V |
| ON_V ${ }_{\text {IL }}$ | ON Pin Input Low Voltage |  | -0.3 | 0 | 0.3 | V |
| SEL[1,0]_V $\mathrm{V}_{\mathrm{IH}}$ | SEL[1,0] pins Input High Voltage |  | 1.65 | -- | 4.5 | V |
| ION(Leakage) | ON Pin Leakage Current | $1 \mathrm{~V} \leq \mathrm{ON} \leq 5 \mathrm{~V}$ or $\mathrm{ON}=\mathrm{GND}$ | -- | -- | 1 | $\mu \mathrm{A}$ |
| THERM ${ }_{\text {ON }}$ | Thermal Protection Shutdown Threshold |  | -- | 125 | -- | ${ }^{\circ} \mathrm{C}$ |
| THERM $_{\text {OFF }}$ | Thermal Protection Restart Threshold |  | -- | 100 | -- | ${ }^{\circ} \mathrm{C}$ |
| Notes: |  |  |  |  |  |  |

A $22 \mathrm{~V}, 13.1 \mathrm{~m} \Omega$, 4 A Integrated Power Switch
with $\mathrm{V}_{\text {IN }}$ Lockout Select and MOSFET Current Monitor Output
$\mathrm{T}_{\text {Total_ON }}, \mathrm{T}_{\text {ON_Delay }}$ and Slew Rate Measurement

*Rise and Fall Times of the ON Signal are 100 ns

A $22 \mathrm{~V}, 13.1 \mathrm{~m} \Omega$, 4 A Integrated Power Switch
with $\mathrm{V}_{\text {IN }}$ Lockout Select and MOSFET Current Monitor Output
Typical Performance Characteristics
$\mathrm{RDS}_{\mathrm{ON}}$ vs. Temperature

$I_{\text {ACL }}$ vs. Temperature


A $22 \mathrm{~V}, 13.1 \mathrm{~m} \Omega$, 4 A Integrated Power Switch
with $\mathrm{V}_{\text {IN }}$ Lockout Select and MOSFET Current Monitor Output
Iout vs. MOSFET IDS


Iout vs. Temperature and MOSFET IDS


A $22 \mathrm{~V}, 13.1 \mathrm{~m} \Omega$, 4 A Integrated Power Switch
with $\mathrm{V}_{\text {IN }}$ Lockout Select and MOSFET Current Monitor Output
$\mathrm{V}_{\text {OUT }}$ Slew Rate vs. Temperature and $\mathrm{C}_{\text {SLEW }}$

$\mathrm{T}_{\text {Total_ON }}$ vs. $\mathrm{C}_{\text {SLEW }}$ and Temperature


A $22 \mathrm{~V}, 13.1 \mathrm{~m} \Omega$, 4 A Integrated Power Switch
with $\mathrm{V}_{\text {IN }}$ Lockout Select and MOSFET Current Monitor Output
Timing Diagram - Basic Operation including Active Current Limit Protection


A $22 \mathrm{~V}, 13.1 \mathrm{~m} \Omega, 4$ A Integrated Power Switch
with $\mathrm{V}_{\text {IN }}$ Lockout Select and MOSFET Current Monitor Output
Timing Diagram - Active Current Limit \& Thermal Protection Operation


Timing Diagram - Basic Operation including Active Current + Internal FET SOA Protection


A $22 \mathrm{~V}, 13.1 \mathrm{~m} \Omega$, 4 A Integrated Power Switch
with $\mathrm{V}_{\text {IN }}$ Lockout Select and MOSFET Current Monitor Output

## SLG59H1009V Application Diagram



Figure 1. Test setup Application Diagram

## Typical Turn-on Waveforms



Figure 2. Typical Turn ON operation waveform for $\mathrm{V}_{\mathrm{IN}}=20 \mathrm{~V}, \mathrm{C}_{\mathrm{SLEW}}=10 \mathrm{nF}, \mathrm{C}_{\text {LOAD }}=10 \mu \mathrm{~F}, \mathrm{R}_{\text {LOAD }}=100 \Omega$

A $22 \mathrm{~V}, 13.1 \mathrm{~m} \Omega$, 4 A Integrated Power Switch
with $\mathrm{V}_{\text {IN }}$ Lockout Select and MOSFET Current Monitor Output


Figure 3. Typical Turn ON operation waveform for $\mathrm{V}_{\mathrm{IN}}=20 \mathrm{~V}, \mathrm{C}_{\mathrm{SLEW}}=18 \mathrm{nF}, \mathrm{C}_{\text {LOAD }}=10 \mu \mathrm{~F}, \mathrm{R}_{\text {LOAD }}=100 \Omega$ Typical Turn-off Waveforms


Figure 4. Typical Turn OFF operation waveform for $V_{I N}=20 \mathrm{~V}, \mathrm{C}_{\mathrm{SLEW}}=10 \mathrm{nF}$, no $\mathrm{C}_{\text {LOAD }}, R_{\text {LOAD }}=100 \Omega$

A $22 \mathrm{~V}, 13.1 \mathrm{~m} \Omega$, 4 A Integrated Power Switch
with $\mathrm{V}_{\text {IN }}$ Lockout Select and MOSFET Current Monitor Output


Figure 5. Typical Turn OFF operation waveform for $\mathrm{V}_{\mathrm{IN}}=20 \mathrm{~V}, \mathrm{C}_{\mathrm{SLEW}}=10 \mathrm{nF}, \mathrm{C}_{\text {LOAD }}=10 \mu \mathrm{~F}, \mathrm{R}_{\text {LOAD }}=100 \Omega$ Typical SOA Waveforms


Figure 6. Thermally induced SOA shutdown for $\mathrm{V}_{\mathrm{IN}}=20 \mathrm{~V}, \mathrm{C}_{\mathrm{LOAD}}=10 \mu \mathrm{~F}, \mathrm{I}_{\mathrm{ACL}}=1 \mathrm{~A}, \mathrm{R}_{\mathrm{SET}}=91 \mathrm{k} \Omega$

A $22 \mathrm{~V}, 13.1 \mathrm{~m} \Omega$, 4 A Integrated Power Switch
with $\mathrm{V}_{\text {IN }}$ Lockout Select and MOSFET Current Monitor Output

## Typical FAULT Operation Waveforms



Figure 7. Typical $\overline{\text { FAULT }}$ assertion waveform for $V_{I N}=20 \mathrm{~V}, C_{\text {LOAD }}=10 \mu F, I_{A C L}=1 \mathrm{~A}, R_{\mathrm{SET}}=91 \mathrm{k} \Omega$, switch in $20 \Omega$ load


Figure 8. Typical $\overline{\text { FAULT }}$ de-assertion waveform for $\mathrm{V}_{\mathrm{IN}}=20 \mathrm{~V}, \mathrm{C}_{\text {LOAD }}=10 \mu \mathrm{~F}, \mathrm{I}_{\mathrm{ACL}}=1 \mathrm{~A}$, $R_{\text {SET }}=91 \mathrm{k} \Omega$, switch out $20 \Omega$ load

## A $22 \mathrm{~V}, 13.1 \mathrm{~m} \Omega$, 4 A Integrated Power Switch with $\mathrm{V}_{\text {IN }}$ Lockout Select and MOSFET Current Monitor Output

## Applications Information

## HFET1 Safe Operating Area Explained

Dialog's HFET1 integrated power controllers incorporate a number of internal protection features that prevents them from damaging themselves or any other circuit or subcircuit downstream of them. One particular protection feature is their Safe Operation Area (SOA) protection. SOA protection is automatically activated under overpower and, in some cases, under overcurrent conditions. Overpower SOA is activated if package power dissipation exceeds an internal 5W threshold longer than 2.5 ms . HFET1 devices will quickly switch off (open circuit) upon overpower detection and automatically resume (close) nominal operation once overpower condition no longer exists.

One possible way to have an overpower condition trigger SOA protection is when HFET1 products are enabled into heavy output resistive loads and/or into large load capacitors. It is under these conditions to follow carefully the "Safe Start-up Loading" guidance in the Applications section of the datasheet. During an overcurrent condition, HFET1 devices will try to limit the output current to the level set by the external $\mathrm{R}_{\mathrm{SET}}$ resistor. Limiting the output current, however, causes an increased voltage drop across the FET's channel because the FET's RDS $_{\mathrm{ON}}$ increased as well. Since the FET's RDS ${ }_{O N}$ is larger, package power dissipation also increases. If the resultant increase in package power dissipation is higher/equal than 5 W for longer than 2.5 ms , internal SOA protection will be triggered and the FET will open circuit (switch off). Every time SOA protection is triggered, all HFET1 devices will automatically attempt to resume nominal operation after 160 ms .

## Safe Start-up Condition

SLG59H1009V has built-in protection to prevent over-heating during start-up into a heavy load. Overloading the VOUT pin with a capacitor and a resistor may result in non-monotonic $\mathrm{V}_{\text {OUT }}$ ramping. In general, under light loading on VOUT, $\mathrm{V}_{\text {OUT }}$ ramping can be controlled with $\mathrm{C}_{\text {SLEW }}$ value. The following equation serves as a guide:

$$
\mathrm{C}_{\text {SLEW }}=\frac{\mathrm{T}_{\text {RISE }}}{\mathrm{V}_{\text {IN }}} \times 4.9 \mu \mathrm{~A} \times \frac{20}{3}
$$

where
$\mathrm{T}_{\text {RISE }}=$ Total rise time from $10 \% \mathrm{~V}_{\text {OUT }}$ to $90 \% \mathrm{~V}_{\text {OUT }}$
$\mathrm{V}_{\text {IN }}=$ Input Voltage
$\mathrm{C}_{\text {SLEW }}=$ Capacitor value for CAP pin
When capacitor and resistor loading on VOUT during start up, the following tables will ensure $\mathrm{V}_{\text {OUT }}$ ramping is monotonic without triggering internal protection:

| Safe Start-up Loading for $\mathbf{V}_{\mathbf{I N}}=\mathbf{2 2} \mathbf{V}$ (Monotonic Ramp) |  |  |  |  |
| :---: | :---: | :---: | :---: | :---: |
| Slew Rate (V/ms) | $\mathbf{C}_{\mathbf{S L E W}}(\mathbf{n F})^{\mathbf{2}}$ | $\mathbf{C}_{\text {LOAD }}(\boldsymbol{\mu F})$ | $\mathbf{R}_{\text {LOAD }}(\mathbf{\Omega})$ |  |
| 0.5 | 66.7 | 500 | 80 |  |
| 1.0 | 33.3 | 250 | 80 |  |
| 1.5 | 22.2 | 160 | 80 |  |
| 2.0 | 16.7 | 120 | 80 |  |
| 2.5 | 13.3 | 100 | 80 |  |

Note 2: Select the closest-value tolerance capacitor.

## A $22 \mathrm{~V}, 13.1 \mathrm{~m} \Omega$, 4 A Integrated Power Switch

## with $\mathrm{V}_{\text {IN }}$ Lockout Select and MOSFET Current Monitor Output

Power Dissipation
The junction temperature of the SLG59H1009V depends on different factors such as board layout, ambient temperature, and other environmental factors. The primary contributor to the increase in the junction temperature of the $\mathrm{SLG59H} 1009 \mathrm{~V}$ is the power dissipation of its power MOSFET. Its power dissipation and the junction temperature in nominal operating mode can be calculated using the following equations:

$$
\mathrm{PD}=\mathrm{RDS}_{\mathrm{ON}} \times \mathrm{I}_{\mathrm{DS}}{ }^{2}
$$

where:
PD = Power dissipation, in Watts (W)
RDS $_{\text {ON }}=$ Power MOSFET ON resistance, in Ohms ( $\Omega$ )
$\mathrm{I}_{\mathrm{DS}}=$ Output current, in Amps (A)
and

$$
T_{J}=P D \times \theta_{J A}+T_{A}
$$

where:
$\mathrm{T}_{\mathrm{J}}=$ Junction temperature, in Celsius degrees $\left({ }^{\circ} \mathrm{C}\right)$
$\theta_{\text {JA }}=$ Package thermal resistance, in Celsius degrees per Watt $\left({ }^{\circ} \mathrm{C} / \mathrm{W}\right)$
$\mathrm{T}_{\mathrm{A}}=$ Ambient temperature, in Celsius degrees ( ${ }^{\circ} \mathrm{C}$ )
In current-limit mode, the SLG59H1009V's power dissipation can be calculated by taking into account the voltage drop across the power switch $\left(\mathrm{V}_{\mathbb{I}}-\mathrm{V}_{\mathrm{OUT}}\right)$ and the magnitude of the output current in current-limit mode $\left(\mathrm{l}_{\mathrm{ACL}}\right)$ :

$$
\begin{gathered}
\mathrm{PD}=\left(\mathrm{V}_{\mathrm{IN}^{-}}-\mathrm{V}_{\mathrm{OUT}}\right) \times \mathrm{I}_{\mathrm{ACL}} \text { or } \\
\mathrm{PD}=\left(\mathrm{V}_{\mathrm{IN}}-\left(\mathrm{R}_{\mathrm{LOAD}} \times \mathrm{I}_{\mathrm{ACL}}\right)\right) \times \mathrm{I}_{\mathrm{ACL}}
\end{gathered}
$$

where:
PD = Power dissipation, in Watts (W)
$\mathrm{V}_{\text {IN }}=$ Input Voltage, in Volts (V)
$R_{\text {LOAD }}=$ Load Resistance, in Ohms $(\Omega)$
$\mathrm{I}_{\mathrm{ACL}}=$ Output limited current, in Amps (A)
$V_{\text {OUT }}=R_{\text {LOAD }} \times I_{\text {ACL }}$

## A $22 \mathrm{~V}, 13.1 \mathrm{~m} \Omega$, 4 A Integrated Power Switch <br> with $\mathrm{V}_{\text {IN }}$ Lockout Select and MOSFET Current Monitor Output

## Layout Guidelines:

1. Since the VIN and VOUT pins dissipate most of the heat generated during high-load current operation, it is highly recommended to make power traces as short, direct, and wide as possible. A good practice is to make power traces with an absolute minimum widths of 15 mils ( 0.381 mm ) per Ampere. A representative layout, shown in Figure 9, illustrates proper techniques for heat to transfer as efficiently as possible out of the device;
2. To minimize the effects of parasitic trace inductance on normal operation, it is recommended to connect input $\mathrm{C}_{\mathbb{I N}}$ and output C LOAD low-ESR capacitors as close as possible to the SLG59H1009V's VIN and VOUT pins;
3. The GND pin should be connected to system analog or power ground plane.
4. 2 oz . copper is recommended for high current operation.

## SLG59H1009V Evaluation Board:

A HFET1 Evaluation Board for SLG59H1009V is designed according to the statements above and is illustrated on Figure 9. Please note that evaluation board has D_Sense and S_Sense pads. They cannot carry high currents and dedicated only for RDS evaluation.


Figure 9. SLG59H1009V Evaluation Board

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Figure 10. SLG59H1009V Evaluation Board Connection Circuit

## Basic Test Setup and Connections



Figure 11. SLG59H1009V Evaluation Board Connection Circuit

## EVB Configuration

1. Connect oscilloscope probes to D/VIN, S/VOUT, ON, etc.;
2. Turn on Power Supply and set desired $\mathrm{V}_{\mathrm{IN}}$ from 4.5 V ... 22 V range;

3 .Toggle the ON signal High or Low to observe SLG59H1009V operation.

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Package Top Marking System Definition


1009V - Part ID Field<br>WW - Date Code Field ${ }^{1}$<br>NNN - Lot Traceability Code Field ${ }^{1}$<br>A - Assembly Site Code Field ${ }^{2}$<br>RR - Part Revision Code Field ${ }^{2}$

Note 1: Each character in code field can be alphanumeric A-Z and 0-9
Note 2: Character in code field can be alphabetic A-Z

A $22 \mathrm{~V}, 13.1 \mathrm{~m} \Omega$, 4 A Integrated Power Switch
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Package Drawing and Dimensions
18 Lead TQFN Package $1.6 \times 3 \mathrm{~mm}$ (Fused Lead) JEDEC MO-220, Variation WCEE


Top View


Side View

Unit: mm

| Symbol | Min | Nom. | Max | Symbol | Min | Nom. | Max |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| A | 0.50 | 0.55 | 0.60 | D | 2.95 | 3.00 | 3.05 |
| A1 | 0.005 | - | 0.05 | E | 1.55 | 1.60 | 1.65 |
| A2 | 0.10 | 0.15 | 0.20 | L | 0.25 | 0.30 | 0.35 |
| b | 0.13 | 0.18 | 0.23 | L1 | 0.64 | 0.69 | 0.74 |
| e | 0.40 BSC |  |  |  | L2 | 0.15 | 0.20 |
| L3 | 2.34 | 2.39 | 2.44 | L4 | 0.13 | 0.18 | 0.23 |

A $22 \mathrm{~V}, 13.1 \mathrm{~m} \Omega$, 4 A Integrated Power Switch
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SLG59H1009V 18-pin STQFN PCB Landing Pattern


Exposed Pad
(PKG face down)

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$\square$ Recommended Land Pattern (PKG face down)


Note: All dimensions shown in micrometers ( $\mu \mathrm{m}$ )

A $22 \mathrm{~V}, 13.1 \mathrm{~m} \Omega$, 4 A Integrated Power Switch
with VIN Lockout Select and MOSFET Current Monitor Output
Tape and Reel Specifications

| Package Type | \# of <br> Pins | Nominal Package Size [mm] | Max Units |  | Reel \& Hub Size [mm] | Leader (min) |  | Trailer (min) |  | Tape Width [mm] | Part <br> Pitch <br> [mm] |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  |  | per Reel | per Box |  | Pockets | Length [mm] | Pockets | Length [mm] |  |  |
| $\begin{gathered} \hline \text { STQFN } \\ 18 \mathrm{~L} \\ 1.6 \times 3 \mathrm{~mm} \\ 0.4 \mathrm{FFC} \\ \text { Green } \end{gathered}$ | 18 | $1.6 \times 3 \times 0.55$ | 3,000 | 3,000 | 178 / 60 | 100 | 400 | 100 | 400 | 8 | 4 |

## Carrier Tape Drawing and Dimensions

| Package Type | PocketBTM Length | PocketBTM Width | Pocket Depth | Index Hole Pitch | Pocket Pitch | Index Hole Diameter | Index Hole to Tape Edge | Index Hole to Pocket Center | Tape Width |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  | A0 | B0 | K0 | P0 | P1 | D0 | E | F | W |
| $\begin{aligned} & \hline \text { STQFN 18L } \\ & 1.6 \times 3 \mathrm{~mm} \\ & 0.4 \mathrm{FFC} \\ & \text { Green } \end{aligned}$ | 1.78 | 3.18 | 0.76 | 4 | 4 | 1.5 | 1.75 | 3.5 | 8 |



## Recommended Reflow Soldering Profile

Please see IPC/JEDEC J-STD-020: latest revision for reflow profile based on package volume of $2.64 \mathrm{~mm}^{3}$ (nominal). More information can be found at www.jedec.org.

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Revision History

| Date | Version | Change |
| :---: | :---: | :--- |
| $12 / 12 / 2018$ | 1.02 | Updated style and formatting <br> Updated Charts <br> Added Scopeshots <br> Added Layout Guidelines <br> Fixed typos |
| $10 / 26 / 2016$ | 1.01 | Updated General Description and Features |
| $5 / 13 / 2016$ | 1.00 | Production Release |

